organic compounds

Acta Crystallographica Section E **Structure Reports** Online

ISSN 1600-5368

Bis(3-nitrophenyl) sulfone

Wei Yao, Fang-Shi Li,* Da-Sheng Yu, Mei-Juan Liu and lin-Na Zhu

Department of Applied Chemistry, College of Science, Nanjing University of Technology, Xinmofan Road No. 5, Nanjing 210009, People's Republic of China Correspondence e-mail: fangshi.li@njut.edu.cn

Received 24 June 2008; accepted 24 June 2008

Key indicators: single-crystal X-ray study; T = 294 K; mean σ (C–C) = 0.004 Å; R factor = 0.032; wR factor = 0.087; data-to-parameter ratio = 6.7.

The asymmetric unit of the title compound, C₁₂H₈N₂O₆S, an important diphenyl sulfone derivative, contains one halfmolecule; a mirror plane passes through the SO₂ group. The dihedral angle between the two symmetry-related benzene rings is 40.10 (13)°. An intramolecular $C-H\cdots O$ hydrogen bond results in the formation of a five-membered ring, which adopts an envelope conformation.

Related literature

For related literature, see: Ayyangar et al. (1981); Amer et al. (1989). For bond-length data, see: Allen et al. (1987).



Experimental

Crystal data

$C_{12}H_8N_2O_6S$	V = 646.9 (2) Å ³
$M_r = 308.27$	Z = 2
Orthorhombic, <i>Pmn</i> 2 ₁	Mo $K\alpha$ radiation
a = 20.260 (4) Å	$\mu = 0.28 \text{ mm}^{-1}$
b = 5.9380 (12) Å	T = 294 (2) K
c = 5.3770 (11) Å	$0.30 \times 0.20 \times 0.10 \text{ mm}$

Enraf-Nonius CAD-4

diffractometer
Absorption correction: ψ scan
(North et al., 1968)
$T_{\min} = 0.920, \ T_{\max} = 0.972$
1304 measured reflections

Refinement

Data collection

 $R[F^2 > 2\sigma(F^2)] = 0.032$ $wR(F^2) = 0.086$ S = 1.00674 reflections 101 parameters H-atom parameters constrained

674 independent reflections 624 reflections with $I > 2\sigma(I)$ $R_{\rm int} = 0.028$ 3 standard reflections frequency: 120 min intensity decay: none

$\Delta \rho_{\rm max} = 0.25 \text{ e } \text{\AA}^{-3}$ $\Delta \rho_{\rm min} = -0.22 \text{ e } \text{\AA}^{-3}$ Absolute structure: Flack (1983), with no Friedel pairs Flack parameter: -0.11 (15)

Table 1

Hydrogen-bond geometry (Å, °).

$D - H \cdots A$	D-H	$H \cdot \cdot \cdot A$	$D \cdots A$	$D - \mathbf{H} \cdot \cdot \cdot A$
$C4-H4A\cdots O1$	0.93	2.58	2.928 (4)	102

Data collection: CAD-4 Software (Enraf-Nonius, 1989); cell refinement: CAD-4 Software; data reduction: XCAD4 (Harms & Wocadlo, 1995); program(s) used to solve structure: SHELXS97 (Sheldrick, 2008); program(s) used to refine structure: SHELXL97 (Sheldrick, 2008); molecular graphics: ORTEP-3 for Windows (Farrugia, 1997); software used to prepare material for publication: SHELXL97.

Supplementary data and figures for this paper are available from the IUCr electronic archives (Reference: HK2478).

References

Allen, F. H., Kennard, O., Watson, D. G., Brammer, L., Orpen, A. G. & Taylor, R. (1987). J. Chem. Soc. Perkin Trans. 2, pp. S1-19.

Amer, A., El-Massry, A. M. & Pittman, C. U. (1989). Chem. Scr. 29, 351-352. Ayyangar, N. R., Lugade, A. G., Nikrad, P. V. & Sharma, V. K. (1981). Synthesis, pp. 640-643.

Enraf-Nonius (1989). CAD-4 Software. Enraf-Nonius, Delft, The Netherlands.

Farrugia, L. J. (1997). J. Appl. Cryst. 30, 565.

Flack, H. D. (1983). Acta Cryst. A39, 876-881.

Harms, K. & Wocadlo, S. (1995). XCAD4. University of Marburg, Germany. North, A. C. T., Phillips, D. C. & Mathews, F. S. (1968). Acta Cryst. A24, 351-359

Sheldrick, G. M. (2008). Acta Cryst. A64, 112-122.

supplementary materials

Acta Cryst. (2008). E64, 01378 [doi:10.1107/S160053680801917X]

Bis(3-nitrophenyl) sulfone

W. Yao, F.-S. Li, D.-S. Yu, M.-J. Liu and J.-N. Zhu

Comment

The title compound, (I), is used for preparing 3,3'-diaminodiphenyl sulfone (Ayyangar *et al.*, 1981). As part of our studies in this area, we report herein the synthesis and crystal structure of (I).

The asymmetric unit of (I) (Fig. 1) contains one half molecule. The bond lengths (Allen *et al.*, 1987) and angles are within normal ranges. The dihedral angle between the two symmetry related bezene rings is $139.90(13)^\circ$. The intramolecular C-H···O hydrogen bond (Table 1) results in the formation of a five-membered non-planar ring: (S/O1/C3/C4/H4A), in which it adopts envelope conformation, with O1 atom displaced by -0.494 (3) Å from the planes of the other ring atoms.

Experimental

The title compound, (I), was prepared according to the literature method (Amer *et al.*, 1989). Crystals suitable for X-ray analysis were obtained by dissolving (I) (0.2 g) in dichloroethane (25 ml) and evaporating the solvent slowly at room temperature for about 7 d.

Refinement

H atoms were positioned geometrically, with C-H= 0.93 Å for aromatic H, and constrained to ride on their parent atoms, with $U_{iso}(H) = 1.2U_{eq}(C)$.

Figures



Fig. 1. The molecular structure of the title molecule, with the atom-numbering scheme [symmetry code: (') -x, y, z]. Hydrogen bonds are shown as dashed lines.

Bis(3-nitrophenyl) sulfone

Crystal data $C_{12}H_8N_2O_6S$ $M_r = 308.27$ Orthorhombic, $Pmn2_1$ Hall symbol: P 2ac -2 a = 20.260 (4) Å

 $F_{000} = 316$ $D_x = 1.583 \text{ Mg m}^{-3}$ Mo K α radiation $\lambda = 0.71073 \text{ Å}$ Cell parameters from 25 reflections $\theta = 10-13^\circ$

b = 5.9380 (12) Å	$\mu = 0.28 \text{ mm}^{-1}$
c = 5.3770 (11) Å	T = 294 (2) K
$V = 646.9 (2) \text{ Å}^3$	Block, light yellow
Z = 2	$0.30 \times 0.20 \times 0.10 \text{ mm}$
Data collection	
Enraf–Nonius CAD-4 diffractometer	$R_{\rm int} = 0.028$
Radiation source: fine-focus sealed tube	$\theta_{\rm max} = 25.2^{\circ}$
Monochromator: graphite	$\theta_{\min} = 2.0^{\circ}$
T = 294(2) K	$h = -24 \rightarrow 24$
$\omega/2\theta$ scans	$k = -7 \rightarrow 0$
Absorption correction: ψ scan (North <i>et al.</i> , 1968)	$l = 0 \rightarrow 6$
$T_{\min} = 0.920, \ T_{\max} = 0.972$	3 standard reflections
1304 measured reflections	every 120 min
674 independent reflections	intensity decay: none
624 reflections with $I > 2\sigma(I)$	
Refinement	
Refinement on F^2	H-atom parameters constrained
Least-squares matrix: full	$w = 1/[\sigma^2(F_o^2) + (0.06P)^2 + 0.078P]$ where $P = (F_o^2 + 2F_c^2)/3$

 $R[F^2 > 2\sigma(F^2)] = 0.032$ $(\Delta/\sigma)_{max} < 0.001$
 $wR(F^2) = 0.086$ $\Delta\rho_{max} = 0.25 \text{ e } \text{Å}^{-3}$

 S = 1.00 $\Delta\rho_{min} = -0.22 \text{ e } \text{Å}^{-3}$

 674 reflections
 Extinction correction: SHELXL97 (Sheldrick, 2008), Fc*=kFc[1+0.001xFc^2\lambda^3/sin(2\theta)]^{-1/4}

 101 parameters
 Extinction coefficient: 0.069 (8)

Primary atom site location: structure-invariant direct Absolute structure: Flack (1983), with no Friedel pairs Secondary atom site location: difference Fourier map Flack parameter: -0.11 (15) Hydrogen site location: inferred from neighbouring sites

Special details

Geometry. All e.s.d.'s (except the e.s.d. in the dihedral angle between two l.s. planes) are estimated using the full covariance matrix. The cell e.s.d.'s are taken into account individually in the estimation of e.s.d.'s in distances, angles and torsion angles; correlations between e.s.d.'s in cell parameters are only used when they are defined by crystal symmetry. An approximate (isotropic) treatment of cell e.s.d.'s is used for estimating e.s.d.'s involving l.s. planes.

Refinement. Refinement of F^2 against ALL reflections. The weighted R-factor wR and goodness of fit S are based on F^2 , conventional R-factors R are based on F, with F set to zero for negative F^2 . The threshold expression of $F^2 > 2 \text{sigma}(F^2)$ is used only for calculating R-factors(gt) etc. and is not relevant to the choice of reflections for refinement. R-factors based on F^2 are statistically about twice as large as those based on F, and R- factors based on ALL data will be even larger.

x	у	Ζ	$U_{\rm iso}*/U_{\rm eq}$
0.5000	0.08254 (19)	0.9607 (2)	0.0438 (4)
0.68253 (13)	0.0542 (4)	0.2895 (5)	0.0422 (6)
0.5000	-0.1563 (5)	0.9183 (9)	0.0626 (12)
0.5000	0.1705 (7)	1.2095 (7)	0.0663 (11)
0.66204 (14)	-0.1343 (4)	0.2403 (5)	0.0660 (8)
0.72681 (13)	0.1460 (4)	0.1767 (5)	0.0599 (7)
0.64732 (14)	0.4956 (5)	0.7589 (8)	0.0451 (8)
0.6638	0.6351	0.8072	0.054*
0.59364 (14)	0.4066 (5)	0.8822 (7)	0.0410 (7)
0.5741	0.4842	1.0131	0.049*
0.56929 (13)	0.1978 (5)	0.8063 (5)	0.0347 (7)
0.59799 (14)	0.0791 (4)	0.6139 (6)	0.0341 (6)
0.5816	-0.0603	0.5648	0.041*
0.65163 (13)	0.1743 (5)	0.4973 (6)	0.0356 (6)
0.67683 (14)	0.3828 (4)	0.5672 (7)	0.0410 (7)
0.7130	0.4442	0.4852	0.049*
	x 0.5000 0.68253 (13) 0.5000 0.5000 0.66204 (14) 0.72681 (13) 0.64732 (14) 0.6638 0.59364 (14) 0.5741 0.56929 (13) 0.59799 (14) 0.5816 0.65163 (13) 0.67683 (14) 0.7130	x y 0.5000 0.08254 (19) 0.68253 (13) 0.0542 (4) 0.5000 -0.1563 (5) 0.5000 0.1705 (7) 0.66204 (14) -0.1343 (4) 0.72681 (13) 0.1460 (4) 0.64732 (14) 0.4956 (5) 0.6638 0.6351 0.59364 (14) 0.4066 (5) 0.5741 0.4842 0.56929 (13) 0.1978 (5) 0.59799 (14) 0.0791 (4) 0.5816 -0.0603 0.65163 (13) 0.1743 (5) 0.67683 (14) 0.3828 (4) 0.7130 0.4442	xyz0.50000.08254 (19)0.9607 (2)0.68253 (13)0.0542 (4)0.2895 (5)0.5000-0.1563 (5)0.9183 (9)0.50000.1705 (7)1.2095 (7)0.66204 (14)-0.1343 (4)0.2403 (5)0.72681 (13)0.1460 (4)0.1767 (5)0.64732 (14)0.4956 (5)0.7589 (8)0.66380.63510.80720.59364 (14)0.4066 (5)0.8822 (7)0.57410.48421.01310.56929 (13)0.1978 (5)0.8063 (5)0.59799 (14)0.0791 (4)0.6139 (6)0.5816-0.06030.56480.65163 (13)0.1743 (5)0.4973 (6)0.67683 (14)0.3828 (4)0.5672 (7)0.71300.44420.4852

Fractional atomic coordinates and isotropic or equivalent isotropic displacement parameters (A^2)

Atomic displacement parameters (\AA^2)

	U^{11}	U^{22}	U^{33}	U^{12}	U^{13}	U^{23}
S	0.0316 (5)	0.0543 (6)	0.0455 (7)	0.000	0.000	0.0169 (6)
Ν	0.0448 (13)	0.0450 (14)	0.0367 (14)	0.0071 (11)	0.0003 (12)	-0.0003 (11)
O1	0.0408 (17)	0.0472 (16)	0.100 (3)	0.000	0.000	0.032 (2)
O2	0.049 (2)	0.114 (3)	0.0364 (18)	0.000	0.000	0.016 (2)
O3	0.0784 (19)	0.0580 (15)	0.0615 (18)	-0.0025 (12)	0.0081 (16)	-0.0211 (14)
O4	0.0545 (14)	0.0738 (16)	0.0512 (15)	0.0009 (12)	0.0190 (12)	0.0005 (14)
C1	0.0374 (14)	0.0341 (14)	0.064 (2)	-0.0016 (12)	-0.0022 (16)	-0.0079 (16)
C2	0.0370 (15)	0.0400 (15)	0.0460 (17)	0.0078 (12)	-0.0021 (14)	-0.0055 (14)
C3	0.0274 (12)	0.0381 (14)	0.0386 (16)	0.0013 (11)	-0.0031 (12)	0.0081 (13)
C4	0.0341 (13)	0.0323 (12)	0.0359 (16)	-0.0004 (11)	-0.0049 (13)	0.0041 (14)
C5	0.0326 (13)	0.0370 (13)	0.0373 (14)	0.0067 (10)	-0.0038 (13)	0.0026 (13)
C6	0.0353 (14)	0.0364 (14)	0.0511 (19)	-0.0024 (12)	0.0046 (15)	0.0033 (14)

Geometric parameters (Å, °)

S—O2	1.436 (4)	C1—H1B	0.9300
S-01	1.437 (3)	C2—C3	1.395 (4)
S—C3	1.769 (3)	C2—H2B	0.9300
S—C3 ⁱ	1.769 (3)	C3—C4	1.380 (4)
N04	1.212 (4)	C4—C5	1.376 (4)
N—O3	1.223 (3)	C4—H4A	0.9300
N—C5	1.466 (4)	C5—C6	1.391 (4)
C1—C6	1.367 (5)	С6—Н6А	0.9300
C1—C2	1.379 (4)		

supplementary materials

O2—S—O1	120.5 (3)	С3—С2—Н2В	120.7
O2—S—C3	107.24 (14)	C4—C3—C2	121.6 (3)
O1—S—C3	107.92 (15)	C4—C3—S	119.2 (2)
O2—S—C3 ⁱ	107.24 (14)	C2—C3—S	119.2 (3)
O1—S—C3 ⁱ	107.92 (15)	C5—C4—C3	117.7 (3)
C3—S—C3 ⁱ	105.06 (18)	C5—C4—H4A	121.2
O4—N—O3	123.7 (3)	C3—C4—H4A	121.2
O4—N—C5	118.6 (3)	C4—C5—C6	122.2 (3)
O3—N—C5	117.7 (3)	C4—C5—N	119.0 (3)
C6—C1—C2	121.3 (3)	C6—C5—N	118.8 (3)
C6—C1—H1B	119.3	C1—C6—C5	118.6 (3)
C2—C1—H1B	119.3	C1—C6—H6A	120.7
C1—C2—C3	118.6 (3)	С5—С6—Н6А	120.7
C1—C2—H2B	120.7		
C6—C1—C2—C3	-0.4 (5)	S-C3-C4-C5	179.7 (2)
C1—C2—C3—C4	0.6 (5)	C3—C4—C5—C6	-0.1 (4)
C1—C2—C3—S	-179.4 (2)	C3—C4—C5—N	-179.0 (2)
O2—S—C3—C4	152.5 (2)	O4—N—C5—C4	175.0 (3)
O1—S—C3—C4	21.3 (3)	O3—N—C5—C4	-5.2 (4)
C3 ⁱ —S—C3—C4	-93.6 (2)	O4—N—C5—C6	-3.9 (4)
O2—S—C3—C2	-27.5 (3)	O3—N—C5—C6	175.9 (3)
O1—S—C3—C2	-158.6 (3)	C2—C1—C6—C5	0.0 (5)
C3 ⁱ —S—C3—C2	86.4 (3)	C4—C5—C6—C1	0.3 (5)
C2—C3—C4—C5	-0.3 (4)	N-C5-C6-C1	179.2 (3)
Symmetry codes: (i) $-x+1$, y, z.			

Hydrogen-bond geometry (Å, °)

D—H···A	<i>D</i> —Н	H···A	$D \cdots A$	D—H···A
C4—H4A···O1	0.93	2.58	2.928 (4)	102



Fig. 1